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Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/538,395	LIN ET AL.	
Examiner	Art Unit	
Vevgeny Valenrod	1621	

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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
STN structure search, broad, see transcript	3/20/2007	YV
STN structure search, narrow, see transcript	3/20/2007	ΥV
Inventor search, eDAN, EAST (with text) STN (Including NPL)	3/20/2007	YV
STIC search, see transcript	3/7/2007	YV
564/330, 564/123, 161, 163 + EAST text, see transcript	3/20/2007	ΥV
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